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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/037,755	CHO ET AL.	
Examiner	Art Unit	
Erin M. File	2634	

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Class	Subclass	Date	Examiner
375	261	10/7/2005	EMF
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INT	INTERFERENCE SEARCHED		
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SEARCH NOT (INCLUDING SEARCH))
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EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only— see search history printout)	10/7/2005	EMF